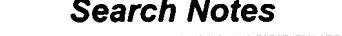


Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/631,346	AGRAWAL ET AL.
	Examiner	Art Unit
	Tan V. Mai	2193

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner